Search Notes				

Application N .	Applicant(s)	
10/087,229	CHOU ET AL.	
Examiner	Art Unit	
Young I Kim	1637	

SEARCHED			
Class	Subclass	Date	Examiner
435	6		
	91.1		
	91.2		
536	23.1		
	24.3		
	24.33	2/6/2004	YJK
	- 104 - 24		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Patent Database (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)		
STN Commercial Database: see enclosed search strategy for the list of databases		
See enclosed search strategies	2/6/2004	YJK